

Full Wafer Test System

Single Touchdown High Volume Production Test Solution



* Shown with a dual chuck prober, dual FOUP loader and two independent FOX-1P test systems

SYSTEM BENEFITS

- **Enables High Throughput, Single Touchdown, Full Wafer Production Testing**
 - ◆ Capable of simultaneously testing up to 16,000 die in a single wafer touchdown
 - ◆ Resource configurable up to 16,384 “Universal Channels” - each programmable as an I/O, Clock, Pin Parametric Measurement Unit (P PMU) or Device Power Supply (DPS)
 - ◆ Software-enabled per site flexibility to support small and large device pin count test needs
- **Comprehensive functional and parametric test capabilities**
 - ◆ Deep functional pattern data and capture memory optimized for BIST/DFT testing
 - ◆ Per channel PMU for per site parametric testing
 - ◆ Individual channel over-current protection to protect wafers and probe cards
- **Configured for high volume production**
 - ◆ Compatible with industry standard probers and probe cards
 - ◆ Available as an integrated test cell with prober, probe cards and 16,384 channel probe I/F
 - ◆ Configurable as a single or dual system integrated test cell

“Changing the Way ICs Are Tested”

CORPORATE HEADQUARTERS

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